

## IN THE CLAIMS

Claims 12-13 have previously been cancelled, without prejudice, as being directed towards a non-elected invention.

Claims 14-16 have previously been cancelled, without prejudice, as being directed towards another non-elected invention.

Please amend claim 1.

Please enter the pending claims, including claims 1-11, as follows:

1. (Currently Amended) A cluster of four copies of a test structure ~~structure~~ disposed ~~near each corner of a die in a space~~ at an intersection of a ~~horizontal scribeline and a vertical scribeline~~ four separate die wherein each copy of said test structure is replicated by photolithography in one of said four separate die and wherein said test structure comprising comprises:

a first set of features ~~at a particular layer of processing a wafer~~, said first set of features being representative of product to be monitored in a chip in said one of said four separate die ~~a subset of product features, said first set of features surrounded with a number of identical features~~; and

a second set of features adjacent to said first set of features, said second set of features being similar to said first set of features, but differing from said first set of features in one or more ways such that pattern recognition results in an

unambiguous and correct identification of said one of said four separate die in  
~~polarity, said polarity referring to placement of an interior of a feature on one side of~~  
~~an edge versus on the other side of the edge.~~

2. (Original) The structure of claim 1 wherein critical dimension (CD) is measured on said first set of features.
3. (Original) The structure of claim 1 wherein said first set of features and said second set of features differ in spaces between features.
4. (Original) The structure of claim 1 wherein said first set of features and said second set of features differ in linewidths of features.
5. (Original) The structure of claim 1 wherein said first set of features and said second set of features have the same pitch for features.
6. (Original) The structure of claim 1 wherein said first set of features comprises a first array of holes.
7. (Original) The structure of claim 6 wherein said first array of holes comprises a 5-by-5 square array of holes.

8. (Original) The structure of claim 6 wherein said second set of features comprises a second array of holes.
9. (Original) The structure of claim 8 wherein said second array of holes differs from said first array of holes in size of array.
10. (Original) The structure of claim 8 wherein said second array of holes differs from said first array of holes in space between holes.
11. (Original) The structure of claim 8 wherein said second array of holes differs from said first array of holes in linewidths of holes.
- 12-16. (Cancelled)